

Scanning Tunneling Microscope (STM)

A scanning tunneling microscope is a powerful tool for obtaining micrographs from conductive and semi conductive materials. The imaging technique has recently been improved for microscopy of nanostructured biomaterials on highly ordered atomic surfaces.

Features:

- Automatic mechanism to approach sample
- Automatic sample and camera moving by software
- Engraving of nanometer-scale surface by lithography
- Ability of tilting (adjusting X, Y axis in sample)
- Ability to view online height and current during scanning
- Ability to change the parameters of the PID, current and voltage during imaging
- Provide 2D and 3D images at nanometer-scale simultaneously
- · Ability to measure the size of material on the image
- Hardware zoom capability for desired more detailed image
- · Software zoom capability for desired area
- Ability to customize the color of image file specification
- Ability to measure the size of material on the image.
- Hardware zoom capability for desired more detailed image
- Software zoom capability for desired area
- Ability to customize the color of image file specification

Performance

- Expandable to suite user needs
- Designed for quick and reliable measurements by experts and novices alike
- Unique price/performance ratio for research and teaching
- Mechanical Stability
- Thermal drift balance
- Low Electronic noise
- Ergonomic Design
- Windows-Based Powerful Software

• Easy Maintenance

Features:

- Capability to change size, angle and location of image by software without handling the sample and ability of automatic offset calculation
- Imaging capability in both constant height and constant current modes with minimum electronic noise
- Ability to display multiple clear and accurate 2D and 3D image files in order to compare them

| STM Software | | |
|--|---|--|
| Various charts of the scan data can be displayed simultaneously | 3D view Image, Line graph, color map | |
| Various charts of the spectroscopy (I-V, I-Z)data offline | Line Graph, first and second derivative , | |
| Noise Reduction and Feature Enhancement | Data filtering in three levels | |
| Lithography Pattern | 16 Color BMP and .dxf files | |
| View all maximum scan range and change parameter | | |
| Data Export | TXT,BMP,JPEG,GIF, | |
| Automatic image transfer to offline processing software Analyzer | | |

| Electronics | |
|-------------------------|---|
| Electronics Size | 55×55×18 cm |
| Power Supply | 220 V~/ 50 Hz/ 1A |
| Computer Interface | 16 bit Data Acquisition Hardware |
| Scan Speed | Up to 100 Line/s at 128 data point / line |
| Scan Image Rotation | 0 - 360° |
| Sample Tilt | Automatically by software |
| Spectroscopy Modes | Single point measurement |
| Spectroscopy Data Point | Up to 2000 |

| STM MEASUREMENT | | |
|-----------------------|---|--|
| Maximum Scan Range | 8-16 μm | |
| Maximum Z-Range | 3μm | |
| Drive Resolution Z | 0.045 nm | |
| Drive Resolution X, Y | 0.12 nm | |
| Current Set Point | 0.02 -100 nA in 3 pA steps | |
| Imaging Modes | Constant current(Topography), Constant Height (Current) | |
| Spectroscopy Modes | Current-Voltage, Current-Distance | |
| Lithography Modes | Bitmap, Vector and Manual | |
| Tip Voltage | ±10 V in 0.3 mV steps | |
| Sample Approach | Fully automatic and manual control | |
| Sample Size | Max 20 mm diameter | |



- 🖓 No.78, 16 Azar St, Keshavarz Blv, Tehran, IRAN
- 📞 (+98 21) 88 980 173 🖨 (+98 21) 88 980 827